

## VISIT #2: The Institute of Electronics Microelectronics and Nanotechnology IEMN

**Schedule** : 09h00 - 11h30

**Location** : 20 minutes from Lille Grand Palais by metro (Station "4 Cantons")

Laboratoire Central – Cité Scientifique – Avenue Poincaré  
59652 VILLENEUVE D'ASCQ CEDEX

**Quantity** : 30 visitors maximum

**Mandatory** : a scanned copy of your valid ID is to be sent before August 1st to the organizers at [erf2016@aaaf.asso.fr](mailto:erf2016@aaaf.asso.fr)



The Institute of Electronics, Microelectronics and Nanotechnology (IEMN) was founded in 1992 with the support of regional college of engineering and universities (Lille1, ISEN-Lille, UVHC) and the CNRS (National Center for Scientific Research). Today, nearly 500 people work together in scientific fields ranging from information and communication technologies (micro and nano-technologies) to physics and acoustics. The visit of IEMN will be focused on its main facilities: Micro and Nanofabrication platform, Microwave Measurements, Near-Field Platform, and Sensors / actuators & Microfluidics lab. Please note that a very significant part of these means is opened to the national scientific community, in the framework of the Base Technological Network (BTR)

### ***Micro and Nanofabrication platform***

The structure is organized in six technological resources: material growth, lithography, deposition, etching, characterization and integration. 1600 m<sup>2</sup> of clean-room area and 26 people are devoted to support the research activities in those innovation areas. Moreover, the clean-room is ISO6 certified.



### ***Microwave Measurement Facility***

The electrical characterization platform gathers IEMN common equipment for measuring the main electrical parameters of devices in a large area of 350m<sup>2</sup>.

These experiments and experimental techniques could be divided in 6 sub-laboratories:

- Wide frequency range capability - THz characterization
- Nanodevices characterization
- Characterization over a wide temperature range
- Low noise characterization
- Non linear characterization
- MEMS characterization



### ***Near-Field Platform***

The IEMN Scanning Probe Microscopy platform supplies premium tools to observe and manipulate atoms and nanometric objects with 8 microscopes on a large area of 250m<sup>2</sup>



### ***Sensors / Actuators & Microfluidics lab***

IEMN recently opened a new lab dedicated for the characterization of Sensors / Actuators in particular in the fields of Microfluidics.

